Issue Classification



Appl	ication	/Contr	ol No
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10705591

Examiner

Han, Jason M

Applicant(s)/Patent Under Reexamination

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Art Unit

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Şandra O'Shea

Supervisory Patent Examiner (Primary Examiner)

U.S. Patent and Trademark Office

4/27/2007

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Jason Moon Han

(Assistant Examiner)

(Legal instruments

Examiner)

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O.G. Print Figure

2

Total Claims Allowed:

O.G. Print Claim(s)

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